













SN74LVC1G11

SCES487H-SEPTEMBER 2003-REVISED NOVEMBER 2016

SN74LVC1G11 Single 3-Input Positive-AND Gate

Features

- Latch-Up Performance Exceeds 100 mA Per JESD 78. Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 1000-V Charged-Device Model (C101)
- Available in the Texas Instruments NanoFree™ Package
- Supports 5-V V_{CC} Operation
- Inputs Accept Voltages to 5.5 V
- Maximum t_{pd} of 4.1 ns at 3.3 V
- Low Power Consumption, 10- μ A Maximum I_{CC}
- ±24-mA Output Drive at 3.3 V
- Ioff Supports Partial-Power-Down Mode Operation

Applications

- **AV Receivers**
- **DLP Front Projection System**
- **Digital Picture Frames**
- Digital Radio
- Digital Still Cameras
- Digital Video Cameras (DVC)
- Embedded PCs
- E-Books
- **Ethernet Switchs**
- **GPS: Personal Navigation Devices**
- Handset: Smartphones
- High-Speed Data Acquisition and Generation
- Military: Radar and Sonar
- Mobile Internet Devices
- Notebook PC and Netbooks
- Network-Attached Storage (NAS)
- **Power Line Communication Modems**
- Server PSU
- STB, DVR, and Streaming Media
- Speakers: USB
- Tablets: Enterprise
- Video Broadcasting and Infrastructure: Scalable Platform and IP-Based Multi-Format Transcoders
- Wireless Headsets, Keyboards, and Mice

3 Description

The SN74LVC1G11 performs the Boolean function $Y = A \cdot B \cdot C$ or $Y = \overline{A + B + C}$ in positive logic.

technology is NanoFree package major а breakthrough in IC packaging concepts, using the die as the package.

This device is fully specified for partial-power-down applications using Ioff. The Ioff circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74LVC1G11DBV	SOT-23 (6)	2.90 mm × 1.60 mm
SN74LVC1G11DCK	SC70 (6)	2.00 mm × 1.25 mm
SN74LVC1G11DRY	SON (6)	1.45 mm × 1.00 mm
SN74LVC1G11DSF	SON (6)	1.00 mm × 1.00 mm
SN74LVC1G11YZP	DSBGA (6)	1.41 mm × 0.91 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Logic Diagram (Positive Logic)





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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision G (December 2015) to Revision H	Page
•	Deleted 200-V Machine Model from Features	1
•	Changed pinout images to improve clarity of pin names and pin numbers	3
•	Added DSBGA pin numbers to Pin Functions table	3
•	Added Operating free-air temperature, T _A for BGA package	5
<u>.</u>	Added Receiving Notification of Documentation Updates section	14
С	hanges from Revision F (December2013) to Revision G	Page
•	Added Applications section, Device Information table, ESD Ratings table, Thermal Information table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section.	1
С	hanges from Revision E (December 2011) to Revision F	Page
•	Updated document to new TI data sheet format	1
•	Removed Ordering Information table.	
•	Updated operating temperature range	4

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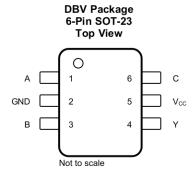
Changes from Revision D (January 2007) to Revision E

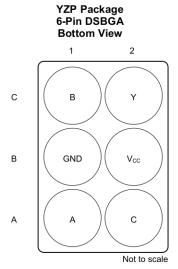
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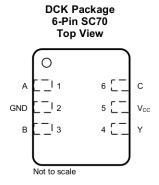
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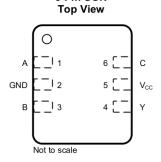


5 Pin Configuration and Functions



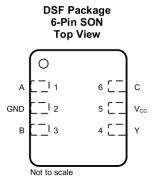






DRY Package

6-Pin SON



See mechanical drawings for dimensions.

Pin Functions

	PIN			
NAME	SOT-23, SC70, SON, SON	DSBGA	I/O	DESCRIPTION
Α	1	A1	I	A Input
В	3	C1	I	B Input
С	6	A2	I	C Input
GND	2	B1	_	Ground
V _{CC}	5	B2	_	Power Supply
Υ	4	C2	0	Y Output

SPACE

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6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{CC}	Supply voltage	-0.5	6.5	V
VI	Input voltage (2)	-0.5	6.5	V
Vo	Voltage applied to any output in the high-impedance or power-off state (2)	-0.5	6.5	V
Vo	Voltage applied to any output in the high or low state ⁽²⁾⁽³⁾	-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current V _I < 0		-50	mA
lok	Output clamp current V _O < 0		-50	mA
Io	Continuous output current		±50	mA
	Continuous current through V _{CC} or GND		±100	mA
T _J	Junction temperature		150	°C
T _{stg}	Storage temperature	-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
.,	., Electrostatic	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	2000	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
V _(ESD) discharge	^{D)} discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

See note⁽¹⁾.

			MIN	MAX	UNIT	
.,	0	Operating	1.65	5.5	.,	
V _{CC}	Supply voltage	Data retention only	1.5		V	
		V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}			
.,	I Bala Javal Sanck calks as	V _{CC} = 2.3 V to 2.7 V	1.7		V	
V _{IH}	High-level input voltage	V _{CC} = 3 V to 3.6 V	2		V	
		V _{CC} = 4.5 V to 5.5 V	0.7 × V _{CC}			
.,	Low-level input voltage	V _{CC} = 1.65 V to 1.95 V		0.35 × V _{CC}		
		V _{CC} = 2.3 V to 2.7 V		0.7	V	
V_{IL}		V _{CC} = 3 V to 3.6 V		0.8	V	
		V _{CC} = 4.5 V to 5.5 V		$0.3 \times V_{CC}$		
V_{I}	Input voltage		0	5.5	V	
Vo	Output voltage		0	V _{CC}	V	
		V _{CC} = 1.65 V		-4		
		V _{CC} = 2.3 V		-8		
I _{OH}	High-level output current	у оу		-16	mA	
		V _{CC} = 3 V		-24		
		V _{CC} = 4.5 V		-32		

 All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. See Implications of Slow or Floating CMOS Inputs, SCBA004.

⁽²⁾ The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽³⁾ The value of V_{CC} is provided in the Recommended Operating Conditions table.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



Recommended Operating Conditions (continued)

See note(1).

			MIN	MAX	UNIT
I _{OL} Low-level output current	V _{CC} = 1.65 V		4		
	V _{CC} = 2.3 V		8		
	V - 2 V		16	mA	
	V _{CC} = 3 V		24		
		V _{CC} = 4.5 V		32	
		V _{CC} = 1.8 V ± 0.15 V, 2.5 V ± 0.2 V		20	
$\Delta t / \Delta v$	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		10	ns/V
		V _{CC} = 5 V ± 0.5 V		10	
T _A Operating free-air temperature	On a rational frame air to proper out the	BGA package	-40	85	°C
	Operating free-air temperature	All other packages	-40	125	C

6.4 Thermal Information

		SN74LVC1G11					
	THERMAL METRIC (1)	DBV (SOT-23)	DCK (SC70)	DRY (SON)	YZP (DSBGA)	DSF (SON)	UNIT
		6 PINS	6 PINS	6 PINS	6 PINS	6 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	195.9	260.1	424.6	105.8	413.7	°C/W
$R_{\theta JCtop}$	Junction-to-case (top) thermal resistance	177.4	98.1	309	1.6	226.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	51.7	63.1	292	10.8	317	°C/W
ΤιΨ	Junction-to-top characterization parameter	61.3	2.2	135.4	3.1	37.4	°C/W
ΨЈВ	Junction-to-board characterization parameter	51.3	62.4	292	10.8	317	°C/W
$R_{\theta JCbot}$	Junction-to-case (bottom) thermal resistance	_	_	_	_	_	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP MAX	UNIT
	$I_{OH} = -100 \mu A$	1.65 V to 5.5 V	V _{CC} - 0.1		
	$I_{OH} = -4 \text{ mA}$	1.65 V	1.2		
V	I _{OH} = -8 mA	2.3 V	1.9		v
V _{OH}	$I_{OH} = -16 \text{ mA}$	3 V	2.4		\ \
	I _{OH} = -24 mA	3 V	2.3		
	$I_{OH} = -32 \text{ mA}$	4.5 V	3.8		
	I _{OL} = 100 μA	1.65 V to 5.5 V		0.1	
	I _{OL} = 4 mA	1.65 V		0.45	
V	I _{OL} = 8 mA	2.3 V		0.3	v
V _{OL}	I _{OL} = 16 mA	3 V		0.4	\ \ \
	I _{OL} = 24 mA	3 V		0.55	
	I _{OL} = 32 mA	4.5 V		0.55	
I _I All inputs	V _I = 5.5 V or GND	0 to 5.5 V		±5	μА
l _{off}	V_I or $V_O = 5.5 V$	0		±10	μА
I _{cc}	$V_I = 5.5 \text{ V or GND}, \qquad I_O = 0$	1.65 V to 5.5 V		10	μА
ΔI _{CC}	One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND	3 V to 5.5 V		500	μА
C _i	V _I = V _{CC} or GND	3.3 V		3.5	pF



6.6 Switching Characteristics, $C_L = 15 \text{ pF}$, $T_A = -40^{\circ}\text{C}$ to +85°C

over recommended operating free-air temperature range, C_L = 15 pF (unless otherwise noted) (see Figure 2)

			, ,			
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{cc}	MIN	MAX	UNIT
t _{pd} A, B, or C		Y	V_{CC} = 1.8 V ± 0.15 V	2.6	15.2	
	A B or C		$V_{CC} = 2.5 V \pm 0.2 V$	1.6	5.6	no
	A, b, or C		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	1.2	4.1	ns
			V _{CC} = 5 V ± 0.5 V	1	3.1	

6.7 Switching Characteristics, $C_L = 30$ pF or 50 pF, $T_A = -40$ °C to +85°C

over recommended operating free-air temperature range, C_L = 30 pF or 50 pF (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{cc}	MIN	MAX	UNIT
t _{pd}	A, B, or C	Y	$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$	2.9	17.2	
			$V_{CC} = 2.5 V \pm 0.2 V$	1.4	6.2	
			$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	1.3	4.9	ns
			$V_{CC} = 5 V \pm 0.5 V$	1	3.5	

6.8 Switching Characteristics, $C_L = 30$ pF or 50 pF, $T_A = -40$ °C to +125°C

over recommended operating free-air temperature range, $C_L = 30 \text{ pF}$ or 50 pF (unless otherwise noted) (see Figure 3)

PARAMETER	METER FROM TO (OUTPUT) VCC		V _{cc}	MIN	MAX	UNIT
	A, B, or C	Y	$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$	2.9	20	
			$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$	1.4	7.8	
^T pd			$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	1.3	6.2	ns
			$V_{CC} = 5 V \pm 0.5 V$	1	4.6	

6.9 Operating Characteristics

 $T_{\wedge} = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	V _{cc}	TYP	UNIT
			V _{CC} = 1.8 V	18	
0	Dower dissination conscitance	f - 40 MU-	V _{CC} = 2.5 V	19	nE
C _{pd}	Power dissipation capacitance	f = 10 MHz	V _{CC} = 3.3 V	20	p⊦
			V _{CC} = 5 V	23	



6.10 Typical Characteristics

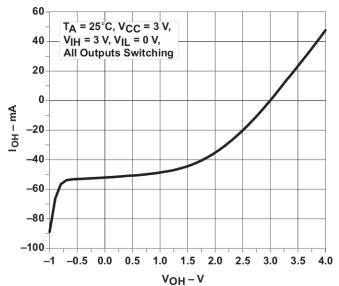


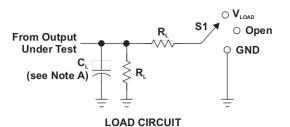
Figure 1. Output Current Drive vs HIGH-level Output Voltage

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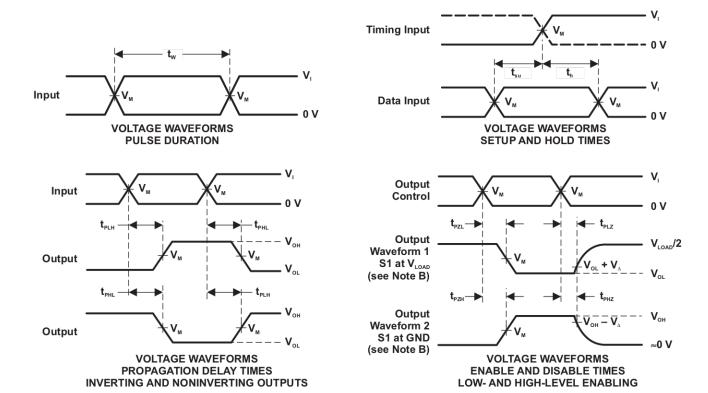


7 Parameter Measurement Information



TEST	S1
t _{PLH} /t _{PHL}	Open
t _{PLZ} /t _{PZL}	V _{LOAD}
t _{PHZ} /t _{PZH}	GND

.,	INI	PUTS		.,			.,
V _{cc}	V,	V ₁ t _r /t _r V _M		V _{LOAD}	C _∟	R _⊾	V _A
1.8 V ± 0.15 V	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	15 pF	1 M Ω	0.15 V
2.5 V ± 0.2 V	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	15 pF	1 MΩ	0.15 V
3.3 V ± 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	15 pF	1 MΩ	0.3 V
5 V ± 0.5 V	V _{cc}	≤2.5 ns	V _{cc} /2	2 × V _{cc}	15 pF	1 M Ω	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{\circ} = 50 Ω .
- D. The outputs are measured one at a time, with one transition per measurement.
- E. $t_{\mbox{\tiny PLZ}}$ and $t_{\mbox{\tiny PHZ}}$ are the same as $t_{\mbox{\tiny dis}}.$
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .
- H. All parameters and waveforms are not applicable to all devices.

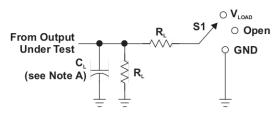
Figure 2. Load Circuit and Voltage Waveforms

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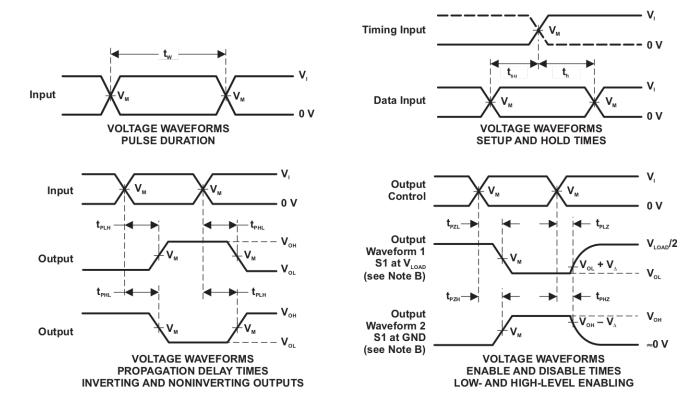
Parameter Measurement Information (continued)



TEST	S1
t _{PLH} /t _{PHL}	Open
$t_{_{\mathrm{PLZ}}}/t_{_{\mathrm{PZL}}}$	$V_{\scriptscriptstyle LOAD}$
$t_{_{PHZ}}/t_{_{PZH}}$	GND

LOAD CIRCUIT

.,	INF	PUTS	.,	.,		_	.,
V _{cc}	V,	t,/t,	V _M	V _{LOAD}	C _∟	R _⊾	V _A
1.8 V ± 0.15 V	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	30 pF	1 k Ω	0.15 V
2.5 V ± 0.2 V	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	30 pF	500 Ω	0.15 V
3.3 V ± 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V
5 V ± 0.5 V	V _{cc}	≤2.5 ns	V _{cc} /2	2 × V _{cc}	50 pF	500 Ω	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z₀ = 50 Ω.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and \dot{t}_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. $t_{\text{\tiny PLH}}$ and $t_{\text{\tiny PHL}}$ are the same as $t_{\text{\tiny pd}}$.
- H. All parameters and waveforms are not applicable to all devices.

Figure 3. Load Circuit and Voltage Waveforms

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8 Detailed Description

8.1 Overview

This 3-input AND gate is designed for 1.65-V to 5.5-V V_{CC} operation.

The SN74LVC1G11 device features a three-input AND gate. The output state is determined by eight patterns of 3-bit input. All inputs can be connected to V_{CC} or GND.

This device is fully-specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

8.2 Functional Block Diagram



Figure 4. Logic Diagram (Positive Logic)

8.3 Feature Description

The SN74LVC1G11 device has a wide operating V_{CC} range of 1.65 V to 5.5 V, which allows use in a broad range of systems. The 5.5-V I/Os allow down translation and also allow voltages at the inputs when V_{CC} = 0 V.

8.4 Device Functional Modes

Table 1 lists the functional modes of SN74LVC1G11.

Table 1. Function Table

	INPUTS	OUTPUT	
Α	В	С	Y
Н	Н	Н	Н
L	Х	Х	L
Х	L	Х	L
Х	Х	L	L



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Validate and test the design implementation to confirm system functionality.

9.1 Application Information

The SN74LVC1G11 device offers logical AND configuration for many design applications. This example describes basic power sequencing using the AND gate configuration. Power sequencing is often used in applications that require a processor or other delicate device with specific voltage timing requirements in order to protect the device from malfunctioning. In the application below, the power-good signals from the supplies tell the MCU to continue an operation.

9.2 Typical Application

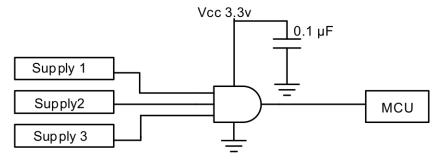


Figure 5. Typical Application Diagram

9.2.1 Design Requirements

- · Recommended input conditions:
 - For rise time and fall time specifications, see $\Delta t/\Delta v$ in the Recommended Operating Conditions table.
 - For specified high and low levels, see V_{IH} and V_{IL} in the *Recommended Operating Conditions* table.
 - Inputs and outputs are overvoltage tolerant and can therefore go as high as 5.5 V at any valid V_{CC}.
- Recommended output conditions:
 - Load currents must not exceed ±50 mA.
- Frequency selection criterion:
 - Figure 6 illustrates the effects of frequency on output current.
 - Added trace resistance and capacitance can reduce maximum frequency capability. Follow the layout practices listed in the *Layout* section.



Typical Application (continued)

9.2.2 Detailed Design Procedure

The SN74LVC1G11 device uses CMOS technology and has balanced output drive. Avoid bus contentions that can drive currents that can exceed maximum limits.

The SN74LVC1G11 allows for performing the logical AND function with digital signals. Maintain input signals as close as possible to either 0 V or V_{CC} for optimal operation.

9.2.3 Application Curve

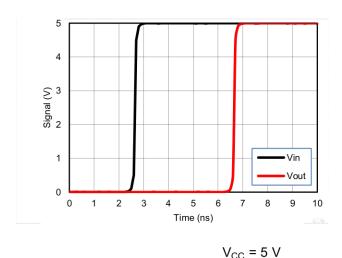


Figure 6. Simulated Input-to-Output Voltage Response Showing Propagation Delay

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating listed in the *Recommended Operating Conditions* table.

To prevent power disturbance, ensure good bypass capacitance for each V_{CC} terminal. For devices with a single-supply, a 0.1- μ F bypass capacitor is recommended. If multiple pins are labeled V_{CC} , then a 0.01- μ F or 0.022- μ F capacitor is recommended for each V_{CC} because the V_{CC} pins are tied together internally. For devices with dual supply pins operating at different voltages, for example V_{CC} and V_{DD} , a 0.1- μ F bypass capacitor is recommended for each supply pin. To reject different frequencies of noise, use multiple bypass capacitors in parallel. Capacitors with values of 0.1 μ F and 1 μ F are commonly used in parallel. Place the bypass capacitor as close to the power terminal as possible for best results.

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11 Layout

11.1 Layout Guidelines

When using multiple-bit logic devices, inputs must never float.

In many cases, functions (or parts of functions) of digital logic devices are unused, for example, when only two inputs of a triple-input AND gate are used or when only 3 of the 4 buffer gates are used. Such input pins must not be left unconnected, because the undefined voltages at the outside connections result in undefined operational states. Figure 7 specifies the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally they are tied to GND or V_{CC} , whichever makes more sense or is more convenient. It is generally acceptable to float outputs, unless the part is a transceiver. If the transceiver has an output enable pin, it disables the output section of the part when asserted, which does not disable the input section of the I/Os. Therefore, the I/Os cannot float when disabled.

11.2 Layout Example

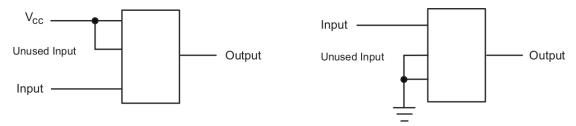


Figure 7. Layout Diagrams



12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- Implications of Slow or Floating CMOS Inputs, SCBA004
- Selecting the Right Texas Instruments Signal Switch, SZZA030

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

NanoFree, E2E are trademarks of Texas Instruments.
All other trademarks are the property of their respective owners.

12.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser based versions of this data sheet, refer to the left hand navigation.



PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74LVC1G11DBVR	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	(C115, C11F, C11K, C11R)	Samples
SN74LVC1G11DBVRE4	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	C11F	Samples
SN74LVC1G11DBVRG4	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	C11F	Samples
SN74LVC1G11DCKR	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	(C35, C3F, C3J, C3 K, C3R)	Samples
SN74LVC1G11DCKRE4	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	C35	Samples
SN74LVC1G11DCKRG4	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	C35	Samples
SN74LVC1G11DRYR	ACTIVE	SON	DRY	6	5000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	C3	Samples
SN74LVC1G11DSFR	ACTIVE	SON	DSF	6	5000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	C3	Samples
SN74LVC1G11YZPR	ACTIVE	DSBGA	YZP	6	3000	RoHS & Green	SNAGCU	Level-1-260C-UNLIM	-40 to 85	C3N	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



PACKAGE OPTION ADDENDUM

10-Dec-2020

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74LVC1G11:

Automotive: SN74LVC1G11-Q1

Enhanced Product: SN74LVC1G11-EP

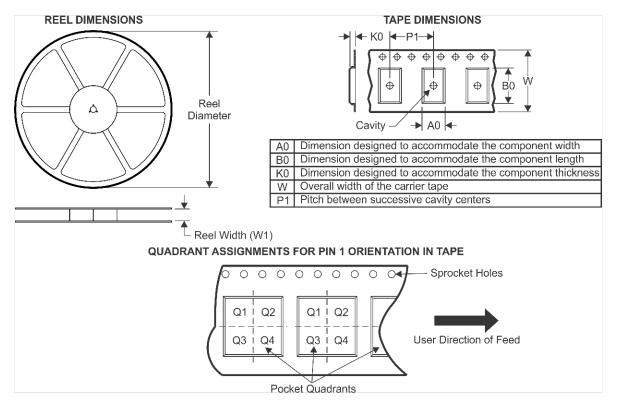
NOTE: Qualified Version Definitions:

- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Enhanced Product Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 6-Jan-2021

TAPE AND REEL INFORMATION



*All dimensions are nominal

All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LVC1G11DBVR	SOT-23	DBV	6	3000	178.0	9.2	3.3	3.23	1.55	4.0	8.0	Q3
SN74LVC1G11DBVR	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
SN74LVC1G11DBVR	SOT-23	DBV	6	3000	178.0	9.0	3.23	3.17	1.37	4.0	8.0	Q3
SN74LVC1G11DBVRG4	SOT-23	DBV	6	3000	178.0	9.0	3.23	3.17	1.37	4.0	8.0	Q3
SN74LVC1G11DCKR	SC70	DCK	6	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
SN74LVC1G11DCKR	SC70	DCK	6	3000	178.0	9.2	2.4	2.4	1.22	4.0	8.0	Q3
SN74LVC1G11DCKRG4	SC70	DCK	6	3000	178.0	9.2	2.4	2.4	1.22	4.0	8.0	Q3
SN74LVC1G11DRYR	SON	DRY	6	5000	180.0	9.5	1.15	1.6	0.75	4.0	8.0	Q1
SN74LVC1G11DSFR	SON	DSF	6	5000	180.0	9.5	1.16	1.16	0.5	4.0	8.0	Q2
SN74LVC1G11YZPR	DSBGA	YZP	6	3000	178.0	9.2	1.02	1.52	0.63	4.0	8.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 6-Jan-2021

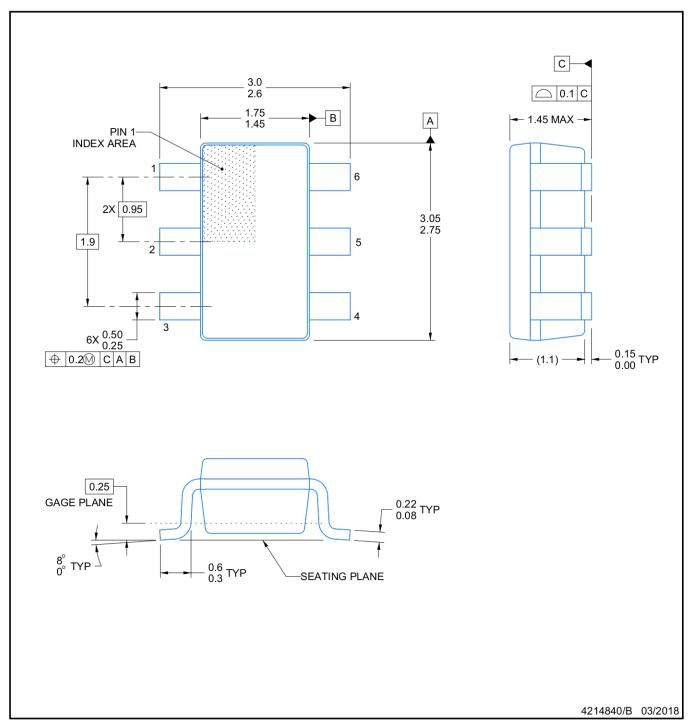


*All dimensions are nominal

7 til dilitoriolorio di o fiorini di							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LVC1G11DBVR	SOT-23	DBV	6	3000	180.0	180.0	18.0
SN74LVC1G11DBVR	SOT-23	DBV	6	3000	202.0	201.0	28.0
SN74LVC1G11DBVR	SOT-23	DBV	6	3000	180.0	180.0	18.0
SN74LVC1G11DBVRG4	SOT-23	DBV	6	3000	180.0	180.0	18.0
SN74LVC1G11DCKR	SC70	DCK	6	3000	180.0	180.0	18.0
SN74LVC1G11DCKR	SC70	DCK	6	3000	180.0	180.0	18.0
SN74LVC1G11DCKRG4	SC70	DCK	6	3000	180.0	180.0	18.0
SN74LVC1G11DRYR	SON	DRY	6	5000	184.0	184.0	19.0
SN74LVC1G11DSFR	SON	DSF	6	5000	184.0	184.0	19.0
SN74LVC1G11YZPR	DSBGA	YZP	6	3000	220.0	220.0	35.0



SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

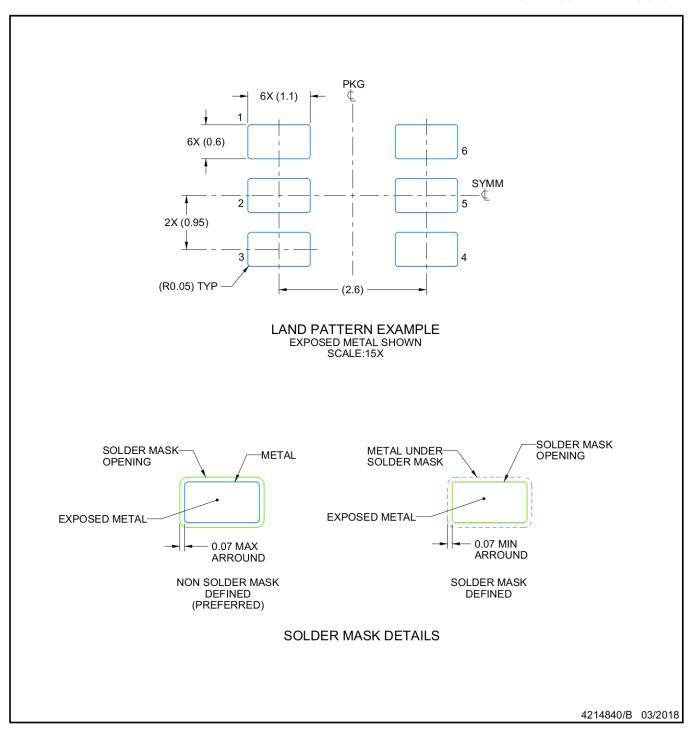
 2. This drawing is subject to change without notice.

 3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

- Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
 Reference JEDEC MO-178.



SMALL OUTLINE TRANSISTOR



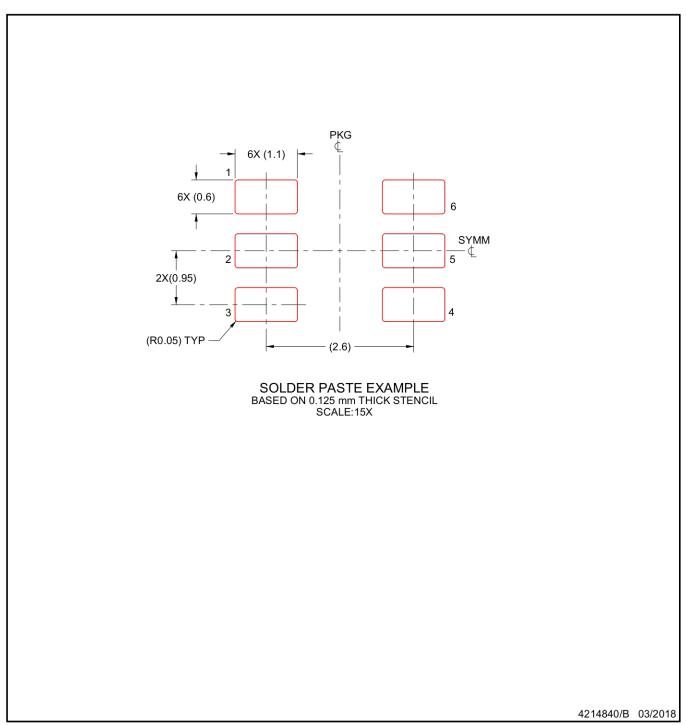
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

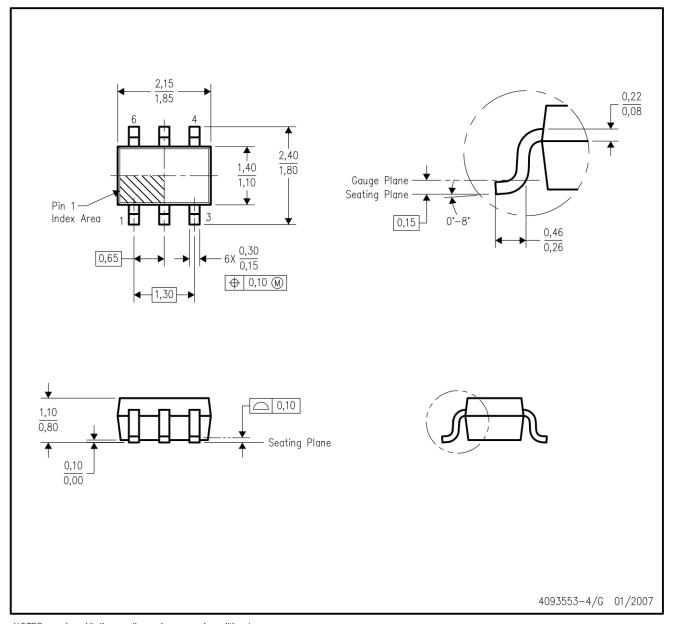
- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

 9. Board assembly site may have different recommendations for stencil design.



DCK (R-PDSO-G6)

PLASTIC SMALL-OUTLINE PACKAGE



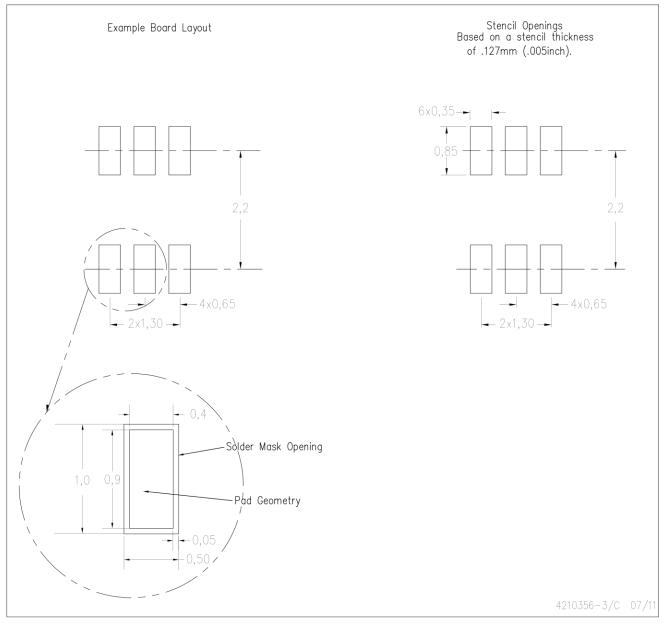
NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
- D. Falls within JEDEC MO-203 variation AB.



DCK (R-PDSO-G6)

PLASTIC SMALL OUTLINE

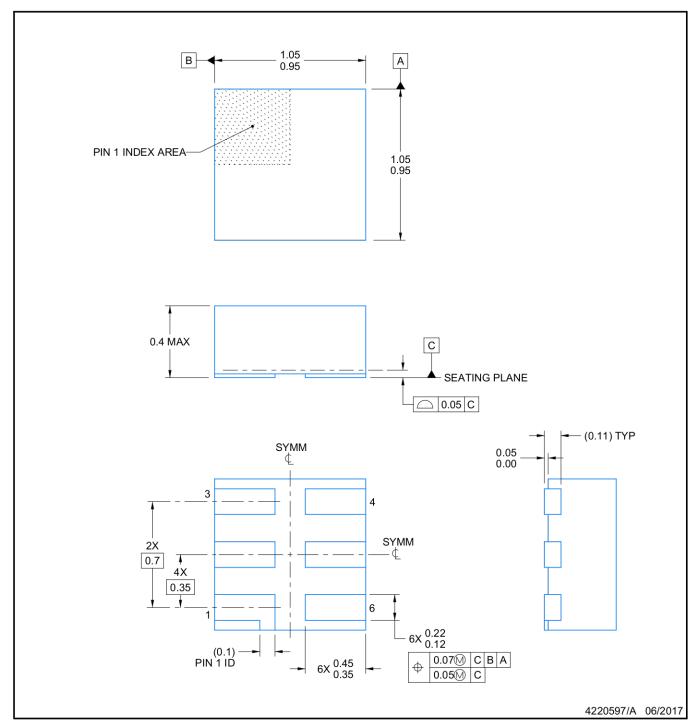


NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.







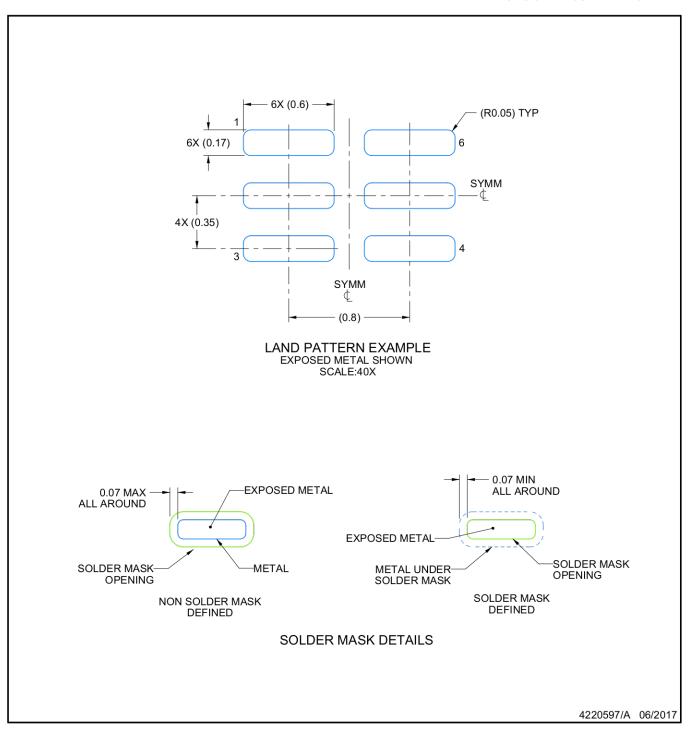
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Reference JEDEC registration MO-287, variation X2AAF.

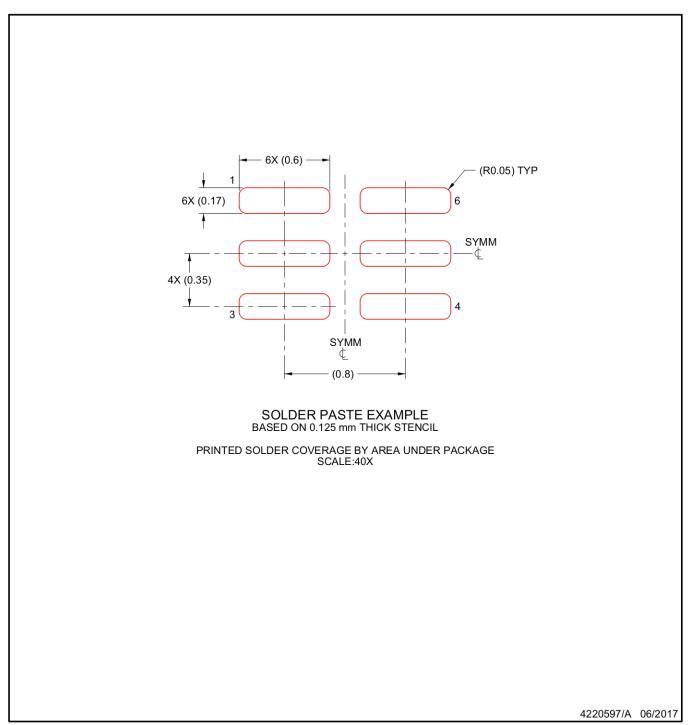




NOTES: (continued)

4. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



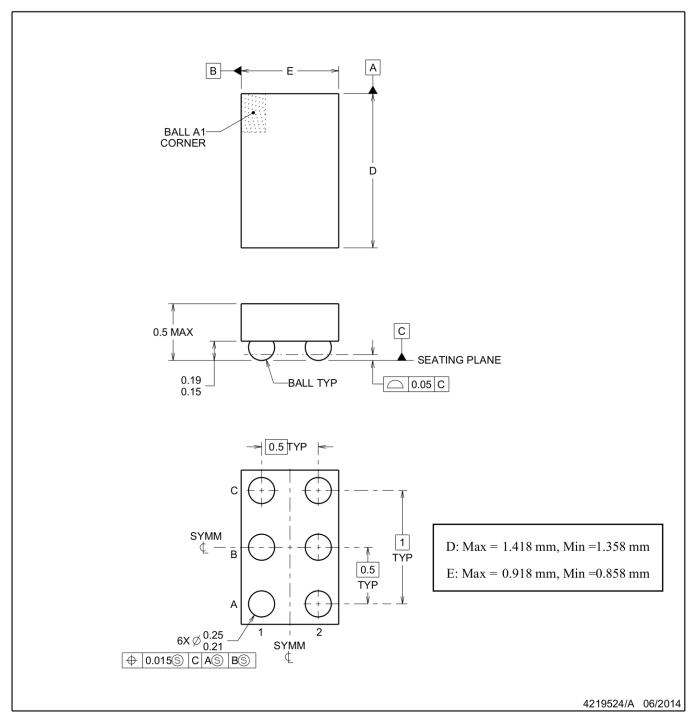


4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





DIE SIZE BALL GRID ARRAY



NOTES:

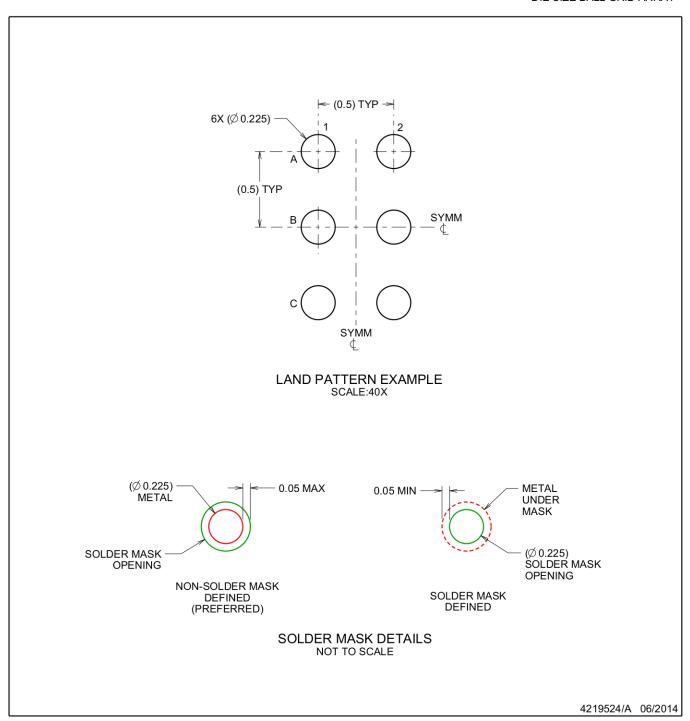
NanoFree Is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.
- 3. NanoFree[™] package configuration.



DIE SIZE BALL GRID ARRAY

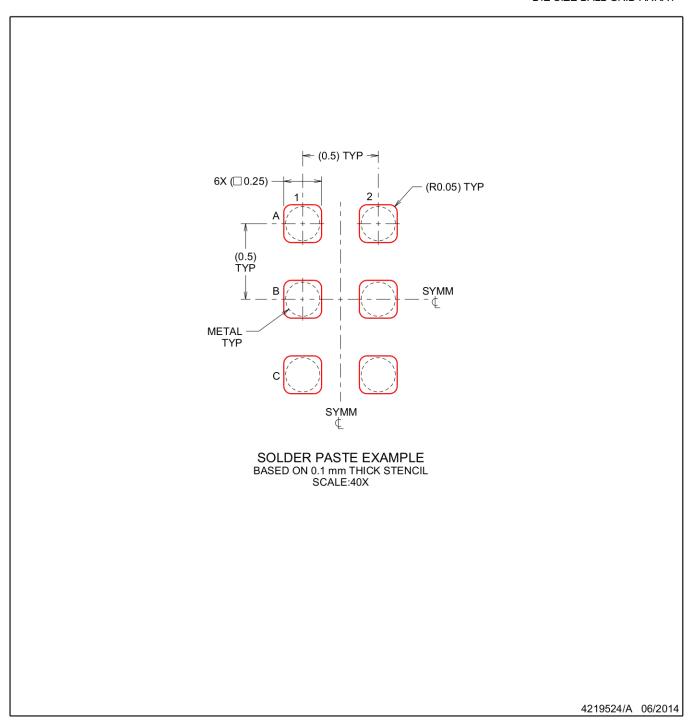


NOTES: (continued)

4. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SBVA017 (www.ti.com/lit/sbva017).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



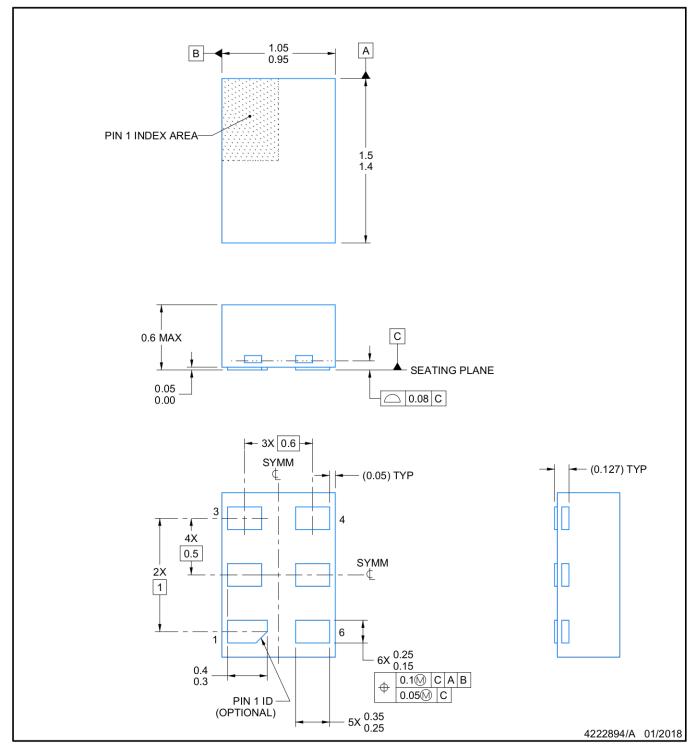


Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4207181/G





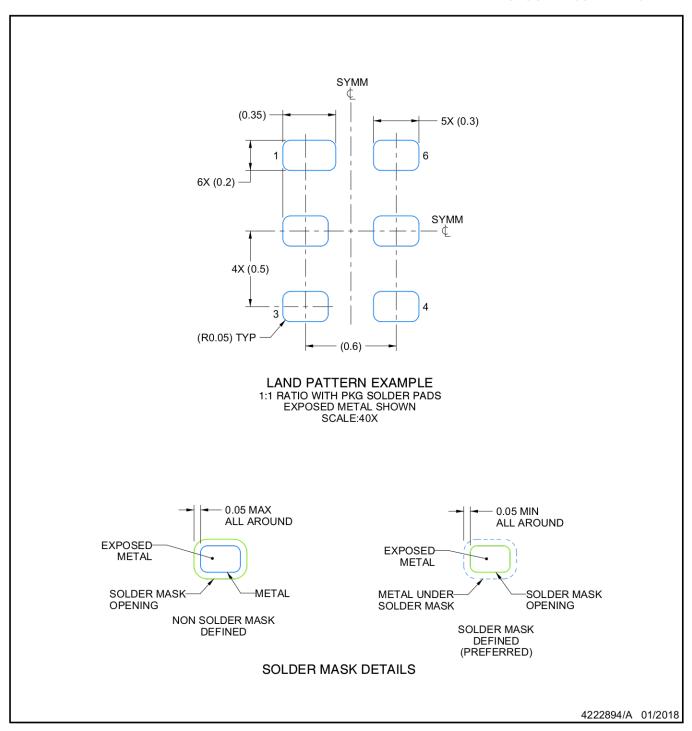


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

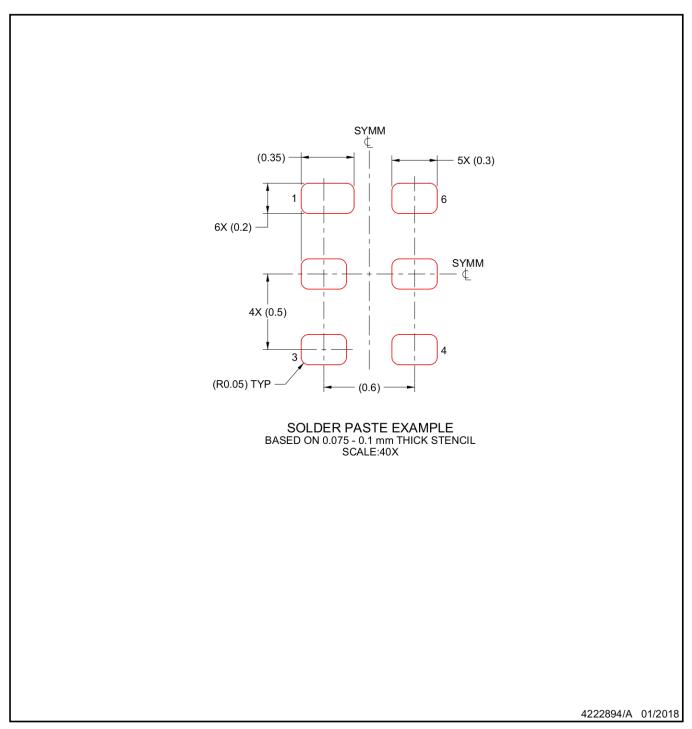




NOTES: (continued)

3. For more information, see QFN/SON PCB application report in literature No. SLUA271 (www.ti.com/lit/slua271).





NOTES: (continued)

Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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